

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/698,945	LEE ET AL.	
Examiner	Art Unit	
James D. Ewart	2683	

SEARCHED			
Class	Subclass	Date	Examiner
370	328	2/10/2006	JDE
	329		
	331		
	332		
	335		
	341-342		
	431		
	441		
	465		
455	62		
•	63.1		
	67.11		
	423		
	424		

INTERFERENCE SEARCHED			
Subclass	Date	Examiner	
above	2/10/2006	JDE	
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	Subclass	Subclass Date	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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/	Search Notes (continued)

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SEARCHED				
Class	Subclass	Date	Examiner	
455	452.1	2/10/2006	JDE	
	452.2			
	509			
	562.1			
	447			
	450			
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
same as	above	2/10/2006	JDE
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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